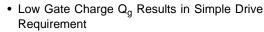
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N-Channel 650V (D-S) Super Junction Power MOSFET

PRODUCT SUMMARY				
V _{DS} (V)	650			
$R_{DS(on)}\left(\Omega\right)$	V _{GS} = 10 V	0.85		
Q _g (Max.) (nC)	15			
Q _{gs} (nC)	3			
Q _{gd} (nC)	6			
Configuration	Single			

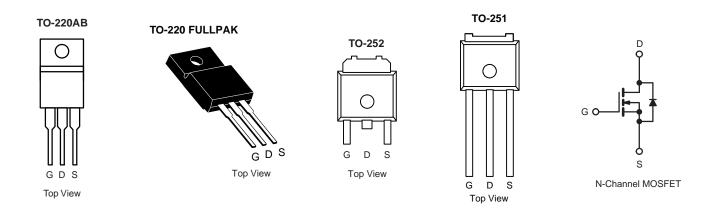
FEATURES





COMPLIANT

- Improved Gate, Avalanche and Dynamic dV/dt Ruggedness
- Fully Characterized Capacitance and Avalanche Voltage and Current
- Compliant to RoHS directive 2002/95/EC



ABSOLUTE MAXIMUM RATINGS T_0	$_{\rm C}$ = 25 °C, unless otherward	vise noted			
PARAMETER	SYMBOL	LIMIT	UNIT		
Drain-Source Voltage	V _{DS}	650	V		
Gate-Source Voltage	V _{GS}	± 30	7 V		
Continuous Drain Current ^e	V_{GS} at 10 V $T_C = 25 ^{\circ}\text{C}$	I _D	4.5	A	
Continuous Drain Current	V_{GS} at 10 V $T_{C} = 25 ^{\circ}\text{C}$ $T_{C} = 100 ^{\circ}\text{C}$		4		
Pulsed Drain Current ^a	I _{DM}	16			
Linear Derating Factor			1.67/0.8/0.3	W/°C	
Single Pulse Avalanche Energy ^b	E _{AS}	120	mJ		
Repetitive Avalanche Current ^a		I _{AR}	34	Α	
Repetitive Avalanche Energy ^a		E _{AR}	17	mJ	
Maximum Power Dissipation	T _C = 25 °C	P _D	205/35/30	W	
Peak Diode Recovery dV/dtc		dV/dt	4.5	V/ns	
Operating Junction and Storage Temperature Range		T _J , T _{stg}	- 55 to + 150	°C	
Soldering Recommendations (Peak Temperature) ^d	for 10 s	· ·]	
Mounting Torque	6-32 or M3 screw		10	lbf ⋅ ir	
	0-32 OF WIS SCIEW		1.1	N · m	

Notes

- a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11). b. Starting T_J = 25 °C, L = 24 mH, R_G = 25 Ω , I_{AS} = 3.2 A (see fig. 12). c. I_{SD} \leq 3.2 A, dI/dt \leq 90 A/µs, V_{DD} \leq V_{DS}, T_J \leq 150 °C.

- d. 1.6 mm from case.
- e. Drain current limited by maximum junction temperature.



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THERMAL RESISTANCE RATINGS					
PARAMETER	SYMBOL	TYP.	MAX.	UNIT	
Maximum Junction-to-Ambient	R _{thJA}	-	62	°C/W	
Maximum Junction-to-Case (Drain)	R _{thJC}	-	3.6/1.2/0.6	C/VV	

PARAMETER	SYMBOL	TES	ST CONDITIONS	MIN.	TYP.	MAX.	UNIT
Static							
Drain-Source Breakdown Voltage	V _{DS}	V _{GS} :	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$		-	-	V
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$	Referenc	Reference to 25 °C, I _D = 1 mA ^d		0.6	-	mV/°C
Gate-Source Threshold Voltage	V _{GS(th)}	V _{DS} =	$V_{DS} = V_{GS}, I_{D} = 250 \mu\text{A}$		-	4.0	V
Gate-Source Leakage	I _{GSS}	V _{GS} = ± 30 V		ı	-	± 100	nA
Zero Gate Voltage Drain Current	I _{DSS}		$V_{DS} = 650 \text{ V}, V_{GS} = 0 \text{ V}$ $V_{DS} = 520 \text{ V}, V_{GS} = 0 \text{ V}, T_{J} = 125 \text{ °C}$		-	10	μA
Drain-Source On-State Resistance	R _{DS(on)}	V _{GS} = 10 V	I _D = 2.5 A ^b	-	-	3.5	Ω
Forward Transconductance	9 _{fs}	V _{DS}	$V_{DS} = 50 \text{ V}, I_{D} = 2.5 \text{ A}$		-	-	S
Dynamic					•		1
Input Capacitance	C _{iss}		$V_{GS} = 0 \text{ V},$ $V_{DS} = 25 \text{ V},$		320	-	-
Output Capacitance	C _{oss}	1			75	-	
Reverse Transfer Capacitance	C _{rss}	f = 1.0 MHz, see fig. 5		-	4	-	
Output Capacitance	C _{oss}		V _{DS} = 1.0 V, f = 1.0 MHz	-	500	-	- pF -
Effective Output Capacitance	C _{oss} eff.	$V_{GS} = 0 V$	$V_{DS} = 520 \text{ V}, f = 1.0 \text{ MHz}$ $V_{DS} = 0 \text{ V to } 520 \text{ V}^{c}$	-	83 14	-	
Total Gate Charge	Qg		I _D = 2.5 A, V _{DS} = 400 V	-	-	15	nC
Gate-Source Charge	Q_{gs}	V _{GS} = 10 V		-	-	3	
Gate-Drain Charge	Q _{gd}		see fig. 6 and 13 ^b	-	-	6	
Turn-On Delay Time	t _{d(on)}		V _{DD} = 325 V, I _D = 3.2 A		18	-	
Rise Time	t _r				40	-	ns
Turn-Off Delay Time	t _{d(off)}	$R_G = 9.1 \Omega$, $R_D = 62 \Omega$, see fig. 10^b		-	50	-	
Fall Time	t _f			-	30	-	
Drain-Source Body Diode Characteristic	s						
Continuous Source-Drain Diode Current	I _S	showing the	/ / : L/		-	4	- A
Pulsed Diode Forward Current ^a	I _{SM}	integral reverse p - n junction diode		i	-	16	
Body Diode Voltage	V _{SD}	$T_J = 25 ^{\circ}\text{C}, I_S = 3.2 \text{A}, V_{GS} = 0 \text{V}^{\text{b}}$		ı	-	1.5	V
Body Diode Reverse Recovery Time	t _{rr}	T _J = 25 °C, I _F = 3.2 A, dl/dt = 100 A/μs ^b		-	180	-	ns
Body Diode Reverse Recovery Charge	Q _{rr}			-	2.1	3.2	μC
Forward Turn-On Time	t _{on}	Intrinsic tu	ırn-on time is negligible (turn-	on is don	ninated by	y L _S and	L _D)

- a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).
- b. Pulse width \leq 300 µs; duty cycle \leq 2 %.
- c. C_{oss} eff. is a fixed capacitance that gives the same charging time as C_{oss} while V_{DS} is rising from 0 % to 80 % V_{DS} .
- d. t = 60 s, f = 60 Hz.

TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted

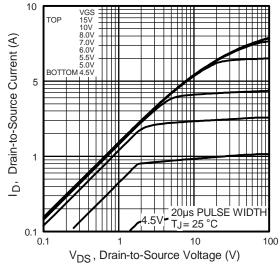
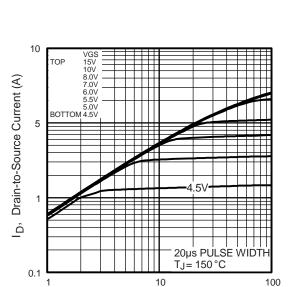


Fig. 1 - Typical Output Characteristics



 $\label{eq:VDS} V_{DS}, \, \text{Drain-to-Source Voltage (V)} \\$ Fig. 2 - Typical Output Characteristics

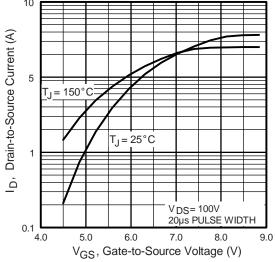


Fig. 3 - Typical Transfer Characteristics

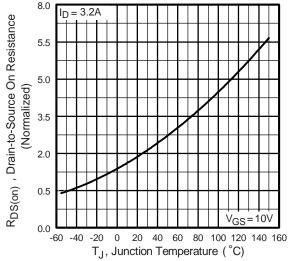


Fig. 4 - Normalized On-Resistance vs. Temperature

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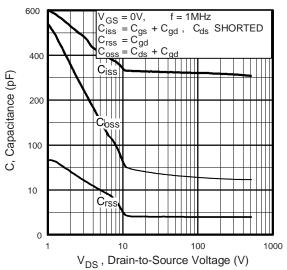


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage

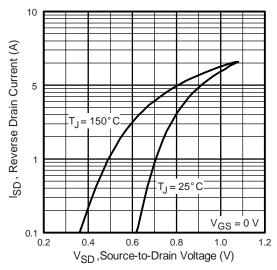


Fig. 7 - Typical Source-Drain Diode Forward Voltage

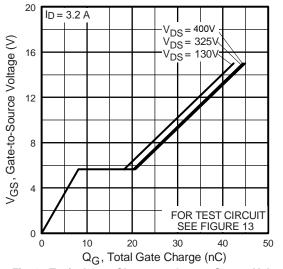


Fig. 6 - Typical Gate Charge vs. Gate-to-Source Voltage

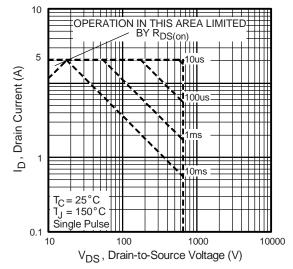


Fig. 8 - Maximum Safe Operating Area

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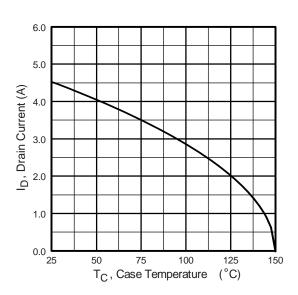


Fig. 9 - Maximum Drain Current vs. Case Temperature

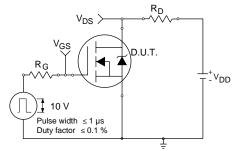


Fig. 10a - Switching Time Test Circuit

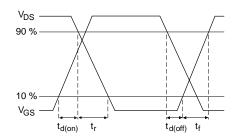


Fig. 10b - Switching Time Waveforms

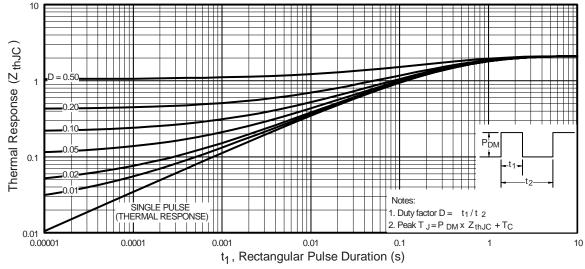


Fig. 11 - Maximum Effective Transient Thermal Impedance, Junction-to-Case

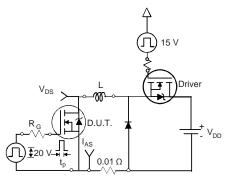


Fig. 12a - Unclamped Inductive Test Circuit

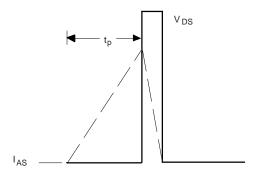


Fig. 12b - Unclamped Inductive Waveforms



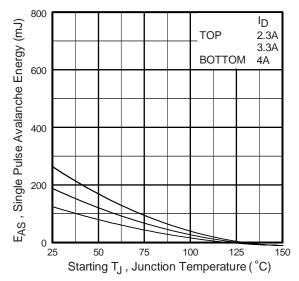


Fig. 12c - Maximum Avalanche Energy vs. Drain Current

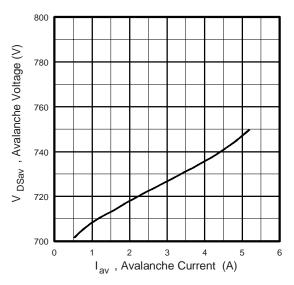


Fig. 12d - Typical Drain-to Source Voltage vs. Avalanche

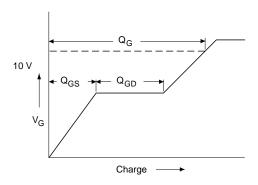


Fig. 13a - Basic Gate Charge Waveform

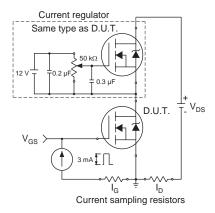
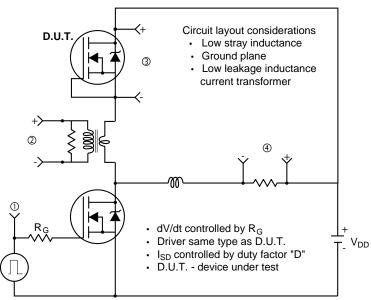
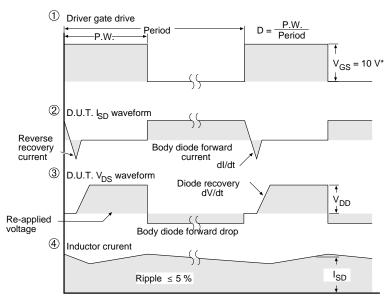


Fig. 13b - Gate Charge Test Circuit

Peak Diode Recovery dV/dt Test Circuit





* V_{GS} = 5 V for logic level devices

Fig. 14 - For N-Channel





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